**Semiconductor Probe**

ECT has a long history manufacturing single-ended and double-ended fine pitch probes. Thanks to our large market exposure at most major semiconductor producers, we have gained substantial expertise from our worldwide customer base. This expertise is reflected in each new probe series we develop, allowing us to stay ahead of the very technically demanding semiconductor market.

Please feel free to contact us for further requirements or more information, as we can meet a variety of special requirements including ultra-high temperature applications or non-magnetic probes for the MEMS market.

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**The ZIP® Advantage**

ECT's ZIP® series feature a number of innovative designs that provide superior contact capable of meeting your application needs. Utilizing ECT’s patented flat technology, ZIP semiconductor spring probes present a new level of accuracy, scalability, and performance. While conventional round technology restricts longer travel and can have its reliability undermined by its small contact area, ZIP possesses a large internal contact area, resulting in lower C-Res, superior bandwidth, and excellent high current behavior. The performance, economy, and application versatility provided by ZIP probes are further enhanced by the use of an external spring. Conventional spring probes rely on contact between the barrel and plunger, which allows for the possibility of conductivity interference through contamination build up in dirty test environments. By having an external spring and no barrel, ZIP greatly reduces the threat of contamination, thereby reducing cost-of-test and increasing efficiency. ECT has produced flat compliant contacts since 1995. The ZIP series is the culmination of years of experience and development, and reflects the industry’s finest semiconductor contacts. With its broad scope of application solutions and special options, the ZIP family of products can satisfy all of your semiconductor test needs. If your spring probes aren’t meeting your tough, high volume challenges, then you don’t know ZIP.

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**Bantam® Series**

The Bantam® probe is a high-performance, spring loaded compliant contact for applications requiring robust, short contact to support fine pitch and high bandwidth production needs. Unlike conventional spring probes, the Bantam has only one internal sliding/wiping contact surface, providing consistent low resistance levels while maintaining a high level of Z-Axis compliance.

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**CSP and SPLJ Series**

These probes are traditional but state of the art double ended probes ranging from 0.4mm to 1.27mm pitch. The CSP probe series offers a selection of different plating options to optimize contact challenges and maximize probe life. Various length options also allow drop-in replacement capability for most competitor probes.

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**Mini-Mite™ Series**

The SCP or Mini-Mite™ probe features a unique single ended design, providing very low, consistent DC resistance. The uniform design allows all three product pitches to be used on the same test height. The single sliding contact cuts the failure mode in half and ensures highly repeatable results.
Ultra HIGH Bandwidth

The Z0 Ultra High Bandwidth Series takes advantage of the ZIP® scalable architecture to arrive at an ultra-compact design with 0.50 nH and 0.60 nH inductance. Z0 offers a bandwidth of 30GHz and 40GHz, making Z0 an ideal solution for high frequency testing.

Mechanical
- Pitch: .016 (0.40)
- Recommended Travel: .018 (0.46)
- Full Travel: .020 (0.50)
- Test Height: .059 (1.51)
- Mechanical Life*: 200,000 cycles
- Operating Temperature: -55°C to +155°C

Spring Force in oz. (grams)

<table>
<thead>
<tr>
<th>Order Code</th>
<th>Test Height</th>
</tr>
</thead>
<tbody>
<tr>
<td>Standard</td>
<td>0.66 (19)</td>
</tr>
<tr>
<td>High</td>
<td>0.96 (27)</td>
</tr>
</tbody>
</table>

Electrical (Static Conditions)
- Current Rating DC: 2.5 amps
- Average DC Probe Resistance**: <90 mOhms
- Self Inductance (Ls): 0.50 nH
- Capacitance (Cc): 0.030 pF
- Bandwidth @ -1dB: >30.0 GHz

Materials and Finishes
- Plunger DUT: HyperCore™
- Plunger HIB: BeCu, Gold plated over hard Nickel
- Spring: Stainless Steel, Gold plated

Tip Style - DUT

<table>
<thead>
<tr>
<th>B</th>
<th>L</th>
<th>D</th>
<th>R</th>
<th>Y</th>
</tr>
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<tbody>
<tr>
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<td></td>
</tr>
</tbody>
</table>

Tip Style - HIB

<table>
<thead>
<tr>
<th>J</th>
</tr>
</thead>
</table>

Spring Force in oz. (grams)

<table>
<thead>
<tr>
<th>Order Code</th>
<th>Test Height</th>
</tr>
</thead>
<tbody>
<tr>
<td>Standard</td>
<td>0.65 (18)</td>
</tr>
<tr>
<td>High</td>
<td>1.11 (31)</td>
</tr>
</tbody>
</table>

Electrical (Static Conditions)
- Current Rating DC: 2.88 amps
- Average DC Probe Resistance**: <90 mOhms
- Self Inductance (Ls): 0.60 nH
- Capacitance (Cc): 0.03 pF
- Bandwidth @ -1dB: >40.0 GHz

Materials and Finishes
- Plunger DUT: HyperCore™
- Plunger HIB: BeCu with proprietary plating
- Spring: Stainless Steel, Gold plated
High Bandwidth

The Z*P® Z High Bandwidth Series yields the highest and most stable bandwidth for its package size. The high performance provided by these contacts makes the Z series a perfect choice for the most demanding test applications. High Bandwidth probes are available in 0.4mm and 0.5mm pitches.

Mechanical
- Pitch: 0.16 (0.40)
- Recommended Travel: 0.025 (0.64)
- Full Travel: 0.028 (0.71)
- Test Height: 0.105 (2.67)
- Mechanical Life*: 500,000 cycles
- Operating Temperature: -55°C to +155°C
- Spring Force in oz. (grams): 1.20 (34)

Electrical (Static Conditions)
- Current Rating DC: 2.0 amps
- Average DC Probe Resistance**: <85 mOhms
- Self Inductance (Ls): 1.07 nH
- Capacitance (Cc): 0.21 pF
- Bandwidth @ -1dB: 30.0 GHz

Materials and Finishes
- Plunger DUT: HyperCore™
- Plunger HIB: BeCu with proprietary plating
- Spring: Stainless Steel, Gold plated

Dimensions in inches (millimeters). Specifications subject to change without notice. Consult factory for other temperature requirements, and applications below -40°C. Stocking Disclaimer: Stocking levels for part numbers listed in this catalog are subject to change. Availability is based on current levels of usage and demand.
**HIGH Bandwidth**

The ZIP® Z High Bandwidth Series yields the highest and most stable bandwidth for its package size. The high performance provided by these contacts makes the Z series a perfect choice for the most demanding test applications. High Bandwidth probes are available in 0.4mm and 0.5mm pitches.

**Z-050**

0.50 mm

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**Mechanical**

- **Pitch:** 0.20 (0.50)
- **Recommended Travel:** 0.25 (0.64)
- **Full Travel:** 0.30 (0.76)
- **Test Height:** 0.110 (2.79)
- **Mechanical Life:** 500,000 cycles
- **Operating Temperature:** -55°C to +155°C
- **Spring Force in oz. (grams):** 1.40 (40)

**Electrical (Static Conditions)**

- **Current Rating DC:** 2.8 amps
- **Average DC Probe Resistance**:** <65 mOhms
- **Self Inductance (Ls):** 1.01 nH
- **Capacitance (Cc):** 0.20 pF
- **Bandwidth @ -1dB:** 25.0 GHz

**Materials and Finishes**

- **Plunger DUT:** HyperCore™
- **Plunger HIB:** BeCu with proprietary plating
- **Spring:** Stainless Steel, Gold plated

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*Life specifications are based on results but are dependent on cleaning frequency and the specific customer application, including DUT materials, handler kit, maintenance, etc.*

**Contact resistance will increase over time due to solder build up and wear.**

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Dimensions in inches (millimeters). Specifications subject to change without notice. Consult factory for other temperature requirements, and applications below -40°C. Stocking Disclaimer: Stocking levels for part numbers listed in this catalog are subject to change. Availability is based on current levels of usage and demand.
Z-KELVIN

ECT's ZIP™ Kelvin .4mm is ideal for voltage sensitive tests on array or peripheral devices requiring milliohm resistance measurements as well as high-power test applications.

**Tip Style - DUT**

<table>
<thead>
<tr>
<th>K</th>
<th>J</th>
</tr>
</thead>
</table>

**Tip Style - HIB**

| J |

**Mechanical**

- **Pitch:** .016 (0.40)
- **Recommended Travel:** .025 (0.64)
- **Full Travel:** .028 (0.71)
- **Test Height:** .105 (2.67)
- **Mechanical Life:** 500,000 cycles
- **Operating Temperature:** -55°C to +155°C
- **Spring Force in oz. (grams):** 1.20 (34)

**Electrical (Static Conditions)**

- **Current Rating DC:** 1.2 amps
- **Average DC Probe Resistance:** <70 mOhms
- **Self Inductance (Ls):** 1.0 nH
- **Capacitance (Cc):** 0.40 pF
- **Bandwidth @ -1dB:** 7.0 GHz

**Materials and Finishes**

- **Plunger DUT:** HyperCore™
- **Plunger HIB:** BeCu with proprietary plating
- **Spring:** Stainless Steel, Gold plated

**Dimensions in inches (millimeters). Specifications subject to change without notice.**

*Contact resistance will increase over time due to solder build-up and wear.*

**Consult factory for other temperature requirements, and applications below -40°C.**

**Stacking Disclaimer: Stacking levels for part numbers listed in this catalog are subject to change. Availability is based on current levels of usage and demand.**

**Note:** Life specifications are based on lab results but are dependent on cleaning frequency and the specific customer application, including DUT materials, handler kit, maintenance, etc.
### Mechanical Specifications

<table>
<thead>
<tr>
<th>Probe Size</th>
<th>Pitch</th>
<th>Recommended Travel</th>
<th>Full Travel</th>
<th>Test Height</th>
<th>Mechanical Life*</th>
<th>Operating Temperature</th>
<th>Spring Force in oz. (grams)</th>
</tr>
</thead>
<tbody>
<tr>
<td>BTM-050</td>
<td>0.019 (0.50)</td>
<td>0.015 (0.38)</td>
<td>0.020 (0.51)</td>
<td>0.098 (2.49)</td>
<td>500,000 cycles</td>
<td>-55°C to +155°C</td>
<td>1.10 (31)</td>
</tr>
<tr>
<td>BTM-075</td>
<td>0.030 (0.75)</td>
<td>0.015 (0.38)</td>
<td>0.020 (0.51)</td>
<td>0.103 (2.62)</td>
<td>500,000 cycles</td>
<td>-55°C to +155°C</td>
<td>1.00 (28)</td>
</tr>
<tr>
<td>BTM-100</td>
<td>0.040 (1.00)</td>
<td>0.028 (0.71)</td>
<td>0.030 (0.76)</td>
<td>0.136 (3.45)</td>
<td>500,000 cycles</td>
<td>-55°C to +155°C</td>
<td>1.40 (39)</td>
</tr>
</tbody>
</table>

### Electrical Specifications (Static Conditions)

<table>
<thead>
<tr>
<th>Probe Size</th>
<th>Current Rating</th>
<th>Average DC Probe Resistance**</th>
<th>Self Inductance (Ls)</th>
<th>Capacitance (Cc)</th>
<th>Bandwidth @ -1dB</th>
<th>Bandwidth @ -1dB</th>
</tr>
</thead>
<tbody>
<tr>
<td>BTM-050</td>
<td>2.5 amps</td>
<td>&lt;50 mOhms</td>
<td>0.95 nH</td>
<td>0.28 pF</td>
<td>23.00 GHz</td>
<td>15.84 GHz</td>
</tr>
<tr>
<td>BTM-075</td>
<td>2.9 amps</td>
<td>&lt;50 mOhms</td>
<td>0.77 nH</td>
<td>0.25 pF</td>
<td>23.00 GHz</td>
<td>15.84 GHz</td>
</tr>
<tr>
<td>BTM-100</td>
<td>3.5 amps</td>
<td>&lt;50 mOhms</td>
<td>1.30 nH</td>
<td>0.34 pF</td>
<td>23.00 GHz</td>
<td>15.84 GHz</td>
</tr>
</tbody>
</table>

### Materials and Finishes

<table>
<thead>
<tr>
<th>Plunger</th>
<th>Heat-treated BeCu, Gold plated over hard Nickel or Primeguard 1 for NiPd solder or Primeguard 2 for Lead free solder</th>
</tr>
</thead>
<tbody>
<tr>
<td>Barrel</td>
<td>Work-hardened BeCu, Gold plated over hard Nickel</td>
</tr>
<tr>
<td>Spring</td>
<td>Steel alloy, Gold plated over hard Nickel</td>
</tr>
</tbody>
</table>

Dimensions in inches (millimeters). Specifications subject to change without notice. Consult factory for other temperature requirements, and applications below -40°C. Stocking Disclaimer: Stocking levels for part numbers listed in this catalog are subject to change. Availability is based on current levels of usage and demand.
CSP4 0.40 mm

**Socket Design Considerations**
- CSP series is captured between the socket body and retainer plate, with the barrel fixed in place.
- SCP Socket series is captured between the socket body and retainer plate, with the barrel sliding freely counter bore.
- Counter bore should not be too deep, and enable a minimum amount of preload against interface board.
- Body height and device cavity should be designed to prevent probe from being compressed shorter than test height.

**Mechanical**
- Pitch: 0.16 (0.40)
- Recommended Travel: 0.20 (0.51)
- Full Travel: 0.25 (0.64)
- Test Height: 0.217 (5.51)
- Mechanical Life*: 250,000 cycles
- Operating Temperature: -55°C to +105°C
- Spring Force in oz. (grams): 0.85 (24)

**Electrical (Static Conditions)**
- Current Rating: 2.0 amps
- Average DC Probe Resistance**: <100 mOhms
- Self Inductance (Ls): 1.71 nH
- Capacitance (Cc): 0.58 pF
- Bandwidth @ -1dB: 6.8 GHz

**Materials and Finishes**
- Plunger DUT: Heat-treated Steel, Gold plated over hard Nickel
- Plunger HIB: Heat-treated Steel, Gold plated over hard Nickel
- Barrel: Work-hardened Phosphorous Bronze, Gold plated over hard Nickel
- Spring: Music Wire, Gold plated

**Tip Style - DUT / HIB**

<table>
<thead>
<tr>
<th>B</th>
<th>L</th>
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<tr>
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</table>
Semiconductor Probe

**CSP5**

0.50 mm

### Mechanical

- **Pitch:** 0.019 (0.50)
- **Recommended Travel:** 0.020 (0.51)
- **Full Travel:** 0.025 (0.64)
- **Test Height:** 0.214 (5.44)
- **Mechanical Life:** 500,000 cycles
- **Operating Temperature:** -55°C to +155°C
- **Spring Force in oz. (grams):** 0.7 (19.8)

### Electrical (Static Conditions)

- **Current Rating:** 2 amps
- **Average DC Probe Resistance:** <150 mOhms
- **Self Inductance (Ls):** 1.5 nH
- **Capacitance (Cc):** 0.63 pF
- **Bandwidth @ -1dB:** 8.13 GHz

### Materials and Finishes

- **Plunger DUT:** Heat-treated BeCu or Steel, Gold plated over hard Nickel or Primeguard 1 for NiPd solder or Primeguard 2 for Lead free solder
- **Plunger HIB:** Heat-treated BeCu or Steel, Hard Gold over Nickel
- **Barrel:** Work-hardened Phosphor Bronze, Gold plated over hard Nickel
- **Spring:** Steel alloy, Gold plated

### Tip Style - DUT / HIB

<table>
<thead>
<tr>
<th>Tip Style</th>
<th>DUT</th>
<th>HIB</th>
</tr>
</thead>
<tbody>
<tr>
<td>B</td>
<td>J</td>
<td>L</td>
</tr>
</tbody>
</table>

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**CSP5-18**

- **Pitch:** 0.019 (0.50)
- **Recommended Travel:** 0.020 (0.51)
- **Full Travel:** 0.025 (0.64)
- **Test Height:** 0.234 (5.94)
- **Mechanical Life:** 500,000 cycles
- **Operating Temperature:** -55°C to +155°C
- **Spring Force in oz. (grams):** 1.2 (34.9)

### Electrical (Static Conditions)

- **Current Rating:** 2 amps
- **Average DC Probe Resistance:** <150 mOhms
- **Self Inductance (Ls):** 1.65 nH
- **Capacitance (Cc):** 0.69 pF
- **Bandwidth @ -1dB:** 7.4 GHz

### Materials and Finishes

- **Plunger DUT:** Heat-treated BeCu or Steel, Gold plated over hard Nickel or Primeguard 1 for NiPd solder or Primeguard 2 for Lead free solder
- **Plunger HIB:** Heat-treated BeCu or Steel, Hard Gold over Nickel
- **Barrel:** Work-hardened Phosphor Bronze, Gold plated over hard Nickel
- **Spring:** Steel alloy, Gold plated

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**CSP5-20**

- **Pitch:** 0.019 (0.50)
- **Recommended Travel:** 0.020 (0.51)
- **Full Travel:** 0.025 (0.64)
- **Test Height:** 0.254 (6.45)
- **Mechanical Life:** 500,000 cycles
- **Operating Temperature:** -55°C to +155°C
- **Spring Force in oz. (grams):** 0.7 (19.8)

### Electrical (Static Conditions)

- **Current Rating:** 2 amps
- **Average DC Probe Resistance:** <150 mOhms
- **Self Inductance (Ls):** 1.79 nH
- **Capacitance (Cc):** 0.75 pF
- **Bandwidth @ -1dB:** 6.8 GHz

### Materials and Finishes

- **Plunger DUT:** Heat-treated BeCu or Steel, Gold plated over hard Nickel or Primeguard 1 for NiPd solder or Primeguard 2 for Lead free solder
- **Plunger HIB:** Heat-treated BeCu or Steel, Hard Gold over Nickel
- **Barrel:** Work-hardened Phosphor Bronze, Gold plated over hard Nickel
- **Spring:** Steel alloy, Gold plated

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**Tip Style - DUT / HIB**

<table>
<thead>
<tr>
<th>Tip Style</th>
<th>DUT</th>
<th>HIB</th>
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</tr>
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</table>

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**CSP5-22**

- **Pitch:** 0.019 (0.50)
- **Recommended Travel:** 0.020 (0.51)
- **Full Travel:** 0.030 (0.76)
- **Test Height:** 0.274 (6.96)
- **Mechanical Life:** 500,000 cycles
- **Operating Temperature:** -55°C to +155°C
- **Spring Force in oz. (grams):** 0.7 (19.8)

### Electrical (Static Conditions)

- **Current Rating:** 2 amps
- **Average DC Probe Resistance:** <150 mOhms
- **Self Inductance (Ls):** 1.89 nH
- **Capacitance (Cc):** 0.79 pF
- **Bandwidth @ -1dB:** 6.2 GHz

### Materials and Finishes

- **Plunger DUT:** Heat-treated BeCu or Steel, Gold plated over hard Nickel or Primeguard 1 for NiPd solder or Primeguard 2 for Lead free solder
- **Plunger HIB:** Heat-treated BeCu or Steel, Hard Gold over Nickel
- **Barrel:** Work-hardened Phosphor Bronze, Gold plated over hard Nickel
- **Spring:** Steel alloy, Gold plated

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**Tip Style - DUT / HIB**

<table>
<thead>
<tr>
<th>Tip Style</th>
<th>DUT</th>
<th>HIB</th>
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ELECTRONIC CONTACT TECHNOLOGY

Semiconductor Probe

CSP8
0.80 mm

Mechanical

- Pitch: .032 (0.80)
- Recommended Travel: .030 (0.76)
- Full Travel: .034 (0.86)
- Test Height: .212 (5.38)
- Mechanical Life*: 500,000 cycles
- Operating Temperature: -55°C to +155°C
- Spring Force in oz. (grams): 1.0 (28.3)

Electrical (Static Conditions)

- Current Rating: 3 amps
- Average DC Probe Resistance**: <150 mOhms
- Self Inductance (Ls): 1.23 nH
- Capacitance (Cc): 0.65 pF
- Bandwidth @ -1dB: 9.23 GHz

Materials and Finishes

- Plunger DUT: Heat-treated BeCu or Steel, Gold plated over hard Nickel or Primeguard 1 for NiPd solder or Primeguard 2 for Lead free solder
- Plunger HIB: Heat-treated BeCu or Steel, Hard Gold over Nickel
- Barrel: Work-hardened Phosphor Bronze, Gold plated over hard Nickel
- Spring: Steel alloy, Gold plated

Tip Style - DUT / HIB

- B
- J
- L

* Life specifications are based on lab results but are dependent on cleaning frequency and the specific customer application, including DUT materials, handler kit, maintenance, etc.
** Contact resistance will increase over time due to solder build-up and wear.
Semiconductor Probe

CSP1
1.0 mm

Mechanical
Pitch: 0.039 (1.0)
Recommended Travel: 0.030 (0.76)
Full Travel: 0.040 (1.02)
Test Height: 0.315 (8.00)
Mechanical Life*: 500,000 cycles
Operating Temperature: -55°C to +155°C
Spring Force in oz. (grams): 2.0 (57)

Electrical (Static Conditions)
Current Rating: 3 amps
Average DC Probe Resistance**: < 100 mΩ
Self Inductance (Ls): 3.10 nH
Capacitance (Cc): 0.95 pF
Bandwidth @ -1dB: 3.80 GHz

Materials and Finishes
Plunger DUT: Heat-treated BeCu, Gold plated over hard Nickel
Plunger HIB: Heat-treated BeCu, Gold plated over hard Nickel
Barrel: Work-hardened Phosphor Bronze, Gold plated over hard Nickel
Spring: Steel alloy, Gold plated

ORDER KEY

BTM-050 / 075 / 100

-1 = Primeguard 1
-2 = Primeguard 2

CSP-1

CSP5 / CSP8

SCP-080 / 100 / 127

- Blank = Gold
- 1 = Primeguard 1
- 2 = Primeguard 2

Tip Style - DUT / HIB

<table>
<thead>
<tr>
<th>Tip Style</th>
<th>DUT</th>
<th>HIB</th>
</tr>
</thead>
<tbody>
<tr>
<td>B</td>
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### Mechanical

**SCP-080**
- Pitch: 0.032 (0.80)
- Recommended Travel: 0.030 (0.76)
- Full Travel: 0.035 (0.89)
- Test Height: 0.200 (5.08)
- Mechanical Life*: 1,000,000 cycles
- Operating Temperature: -55°C to +155°C
- Spring Force in oz. (grams): 1.50 (42.5)

**SCP-100**
- Pitch: 0.039 (1.00)
- Recommended Travel: 0.030 (0.76)
- Full Travel: 0.035 (0.89)
- Test Height: 0.200 (5.08)
- Mechanical Life*: 1,000,000 cycles
- Operating Temperature: -55°C to +155°C
- Spring Force in oz. (grams): 1.50 (42.5)

**SCP-127**
- Pitch: 0.050 (1.27)
- Recommended Travel: 0.030 (0.76)
- Full Travel: 0.035 (0.89)
- Test Height: 0.200 (5.08)
- Mechanical Life*: 1,000,000 cycles
- Operating Temperature: -55°C to +155°C
- Spring Force in oz. (grams): 1.50 (42.5)

### Electrical (Static Conditions)

**SCP-080**
- Current Rating: 5 amps
- Average DC Probe Resistance**: <50 mOhms
- Self Inductance (Ls): 1.27 nH
- Capacitance (Cc): 0.12 pF
- Bandwidth @ -1dB: 6.0 GHz

**SCP-100**
- Current Rating: 7 amps
- Average DC Probe Resistance**: <50 mOhms
- Self Inductance (Ls): 1.40 nH
- Capacitance (Cc): 0.66 pF
- Bandwidth @ -1dB: 6.7 GHz

**SCP-127**
- Current Rating: 9 amps
- Average DC Probe Resistance**: <50 mOhms
- Self Inductance (Ls): 1.40 nH
- Capacitance (Cc): 0.79 pF
- Bandwidth @ -1dB: 7.6 GHz

### Materials and Finishes

**SCP-080**
- Plunger: Heat-treated BeCu, Gold plated over hard Nickel
- Barrel: Work-hardened BeCu, Gold plated over hard Nickel
- Spring: Steel alloy, Gold plated

**SCP-100**
- Plunger: Heat-treated BeCu, Gold plated over hard Nickel
- Barrel: Work-hardened BeCu, Gold plated over hard Nickel
- Spring: Steel alloy, Gold plated

**SCP-127**
- Plunger: Heat-treated BeCu, Gold plated over hard Nickel
- Barrel: Work-hardened BeCu, Gold plated over hard Nickel
- Spring: Steel alloy, Gold plated

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*Life specifications are based on lab results but are dependent on cleaning frequency and other specific customer application, including DUT materials, handler kit, maintenance, etc.*